

Chroma 11300 bias current test system is an integration test system of LCR Meter and Bias Current Source.

It consists of Chroma 3252/3302 series Automatic Component Analyzer and Chroma 1320 series Bias Current Source. The Chroma 1320 series bias current source output can be controlled by Chroma 3252/3302 LCR meter directly. The bias current output capacity can be selected up to 100A to satisfy various testing in R&D, QC, QA, and production applications.

This system is designed for large DC current testing, up to 300A. The connector between bias current sources is low ESR (<10m ohm) design to reduce heat effect and get more accurate measurement result. The multi-function four terminal test fixture supports various DUT, include SMD DUT and DIP ring core DUT.

This system provides power choke characteristic sweep graph analysis through Windows® base software or sweep function of the meter. The bias current scan triggered automatically or manually can analyze the iron core characteristics in inductor for quality inspection and product feature analysis. The Chroma 11300 is a just right test solution for magnetic choke and core used in various power supply.

ORDERING INFORMATION

- 11300** : Bias Current Test System
- A113006** : 19" Rack 35U for Model 11300
- A113007** : 19" Rack 20U for Model 11300
- A113008** : Four terminal test fixture for DIP 100A
- A113009** : Four terminal test fixture for SMD 60A (combined with A113008)
- A113010** : Four terminal PCB for SMD 100A (combined with A113008)
- A113012** : Vacuum Generator for A113009
- A113014** : Vacuum Pump for A113009
- A113017** : LCR Analysis Software
- LCR Meter** : Refer to 3252, 3302
- Bias Current Source** : Refer to 1320, 1320S

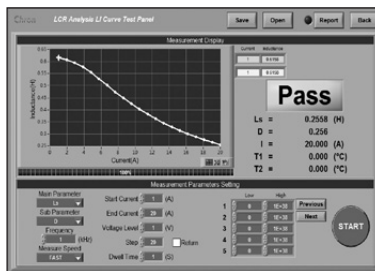
300A

KEY FEATURES

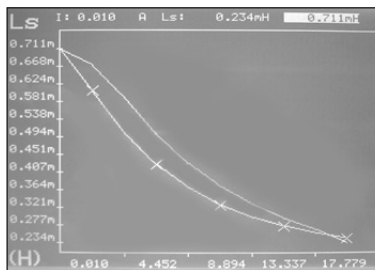
- High efficiency, forward / reverse current switching capability and sweep function
- High stability, frequency response from 20Hz to 1MHz
- High accuracy, 3% output current accuracy
- Expansion capabilities, up to 100A
- Vertical design, easy to maintain
- Flexible modular test system
- Multi-channel intakes in the front panel of rack and multi-fans exhausts in the back of rack
- Multi-function four terminal test fixture
- Low ESR (< 10m ohm) design for connectors between bias current sources
- Windows® based software
- Up to 300A by customization



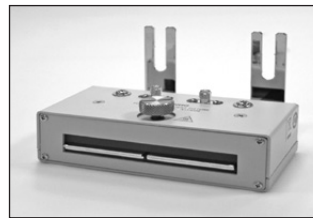
19" Rack 20U for Model 11300



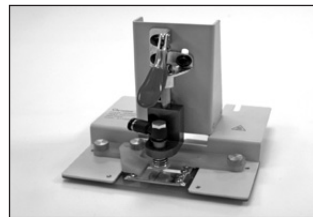
L-I Curve Software



Graphical Bias Current Characteristic Analysis



A113008 :
Four terminal test fixture for DIP 100A



A113009 :
Four terminal test fixture for SMD 60A (combined with A113008)

SPECIFICATIONS

Model	11300					
Output Bias Current	20A	40A	60A	80A	100A	100A~300A
LCR Meter						
Model 3252/3302	•	•	•	•	•	*
Bias Current Source						
Model 1320	•	•	•	•	•	*
Model 1320S		1 Set	2 Sets	3 Sets	4 Sets	*
General						
19"Rack		20U			35U	*
Power Requirements			180~264Vac, 47~63Hz			*

* Call for availability

All specifications are subject to change without notice.

Battery Test & Automation Solution
Photovoltaic Test & Automation Solution
Semiconductor/IC Test Solution
Optical Devices Test Solution
LED/Lighting Test Solution
FPD Test Solution
Video & Color Test Solution
Automated Optical Inspection Solution
Power Electronics Test Solution
Passive Component Test Solution
Electrical Safety Test Solution
General Purpose Test Solution
Thermoelectric Test & Control Solution
PXI Test & Measurement Solution
Manufacturing Execution Systems Solution